Supporting Information

Significant enhancement of conductance for a hybrid

layered molybdate semiconductor by light or heat

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1. EXPERIMENTAL SECTION

Materials and measurements

All commercially available chemicals were of analytical reagent grade and used as received without further purification. Elemental analyses for C, H, N and O were carried out on a Vario MICRO CHNOS Elemental Analyzer. IR spectra were measured on a PerkinElmer Spectrum One FT-IR spectrometer using KBr pellets. UV-vis absorption spectra were measured in the diffuse reflectance mode on a PerkinElmer Lambda 950 UV/vis/near-IR spectrophotometer equipped with an integrating sphere, and a BaSO4 plate was used as the reference. PXRD patterns were recorded using Cu-Ka radiation on a Rigaku Desktop MiniFlexII diffractometer powered at 30 kV and 15 mA. Thermogravimetric analyses (TGA) were performed on a on a Mettler TOLECO TGA apparatus with a heating rate of 10 °C/min in nitrogen atmosphere. Electron paramagnetic resonance (EPR) spectra were recorded on a Bruker ER-420 spectrometer with a 100 kHz magnetic field in the X band at room temperature. XPS studies were performed in a ThermoFisher ESCALAB 250Xi X-ray photoelectron spectrometer (powered at 150 W) using Al- $K\alpha$ radiation. Temperature-dependent electrical conductivities and I-V curves were measured in a Keithley 4200-SCS semiconductor parameter analyzer using pellet samples by the two probe method using silver paste.

Synthesis of $EV[Mo_9O_{28}]$ (1, $EV^{2+} = ethyl$ viologen cation). Na₂MoO₄ 2H₂O (0.36 g, 1.5 mmol), EVBr₂ (0.20 g, 0.1mmol) was dissolved in 20 mL H₂O. The pH was adjusted with 4 M HCl to 1. The mixture was then stirred at room temperature for a few minutes and sealed in a 30 mL Teflon-lined autoclave (120 °C, 72 h, autogenous pressure). The resulting colorless crystals of **1** were filtered off, washed with H₂O and EtOH, and dried in air at room temperature. Yield in Mo: 32%. Calcd. (%) for C₁₄H₁₈O₂₈N₂Mo₉: C, 11.02; H, 1.19; N, 1.84; O, 29.35. Found: C, 11.13; H, 1.14; N, 1.92; O, 29.32.

Single-crystal structure determination

Suitable single crystal of compound **1** was carefully selected and glued to thin glass fibers with epoxy resin. Intensity data for single crystal were collected on a Rigaku Mercury CCD diffractometer with graphite-monochromatized Mo $K\alpha$ radiation ($\lambda = 0.71073$ Å). The empirical absorption corrections were performed using the CrystalClear program.¹ The structure was solved and refined on F² by full-matrix leastsquares technique using the SHELX-97 program package.² Anisotropic thermal parameters were applied to all non-hydrogen atoms. The hydrogen atoms bonded to the carbon atoms of EV²⁺ were generated geometrically.

Computational approach

The crystallographic data of **1** was used to build calculation model. Plane wave-based density functional theory (DFT) calculations of the total and partial densities of states were performed using the Cambridge Sequential Total Energy Package (CASTEP) code.³ The exchange-correlation energy was described by the Perdew–Burke–Eruzerhof (PBE) functional within the generalized gradient approximation (GGA).⁴

References

- Molecular Structure Corporation and Rigaku, 2000. *CrystalClear*. Version 1.36. MSC, 9009 New Trails Drive, The Woodlands, TX 77381-5209, USA, and Rigaku Corporation, 3-9-12 Akishima, Tokyo, Japan.
- (a) G. M. Sheldrick, SHELXS-97, Program for Crystal Structure Solution, University of Göttingen: Göttingen, Germany, 1997; (b) G. M. Sheldrick, SHELXL-97, Program for Crystal Structure Refinement, University of Göttingen: Göttingen, Germany, 1997.
- S. J. Clark, M. D. Segall, C. J. Pickard, P. J. Hasnip, M. J. Probert, K. Refson, M. C. Z. Payne, *Kristallogr.*, 2005, **220**, 567.
- 4) J. P. Perdew, K. Burke, M. Ernzerhof, Phys. Rev. Lett., 1996, 77, 3865.

2. ADDITIONAL FIGURES



Fig. S1 Power X-ray diffraction patterns of 1



Fig. S2 Thermogravimetric curve of 1



Fig. S4 XPS of O 1s for $1A,\,1B$ and 1C



Fig. S5 Temperature-dependent electrical conductivities of **1B** and **1C**. Arrhenius law: $\ln \sigma = -E_a/k_BT + \text{constant}$, where E_a is the activation energy.